

INFORMATION DISCLOSURE STATEMENT BY APPLICANT

ATTY. DOCKET NO. *

SERIAL NO.

F070

09/840,558

APPLICANTS

Gerlach, van der Mast, and Scheinfein

FILING DATE

April 23, 2001

GROUP ART UNIT

2881

U.S. PATENT DOCUMENTS

*Examiner Initial	Cite No.	Patent Number	Issue Date	Patentee	Class	Subclass	Filing Date (if appropriate)
PB	A	4,126,781	11/21/78	Siegel	250	281	
PB	B	4,810,879	3/ 7/89	Walker	250	305	
PB	C	4,810,880	3/ 7/89	Gerlach	250	305	
PB	D	4,818,872	4/4/89	Parker et al.	250	309	
PB	E	5,834,770	11/10/98	Holkeboer et al.	250	281	
PB	F	6,218,664	4/17/01	Krans et al.	250	310	

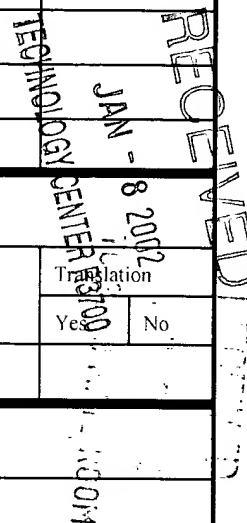
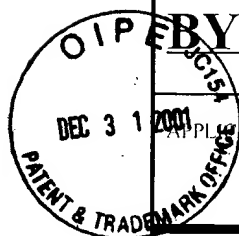
FOREIGN PATENT OR PUBLISHED FOREIGN PATENT APPLICATION

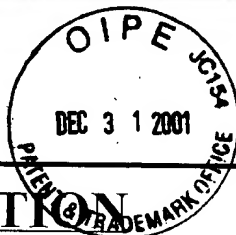
	Cite No.	Document Number	Date	Country	Class	Subclass	Translation
							Yes No

OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)

*Examiner Initial	Cite No.	
PB	H	BAUER, E., KOZIOL, C., LILIENKAMP, G., SCHMIDT, T.; "Spectromicroscopy in a Low Energy Electron Microscope", <u>Journal of Electron Spectroscopy and Related Phenomena</u> , Vol. 84, pp. 201-209(1997).
PB	I	KRANS, J.M. and van ROOY, T.L., "A Miniature Low Voltage SEM with High Resolution", <u>Microscopy and Microanalysis</u> , Vol 5, Supplement 2, pp 2-4, Portland, OR, Aug 1-5, 1999.
PB	J	KRUIT, P. "Auger Electron Spectroscopy in the STEM," <u>Quantitative Microbeam Analysis</u> , Proc. Of the 40 th Scottish Universities Summer School in Physics, August 1993.
PB	K	KRUIT, P., "Magnetic Through-the-lens Detection in Electron Microscopy and Spectroscopy, Part 1" <u>Advances in Optical and Electron Microscopy</u> , Vol. 12 ed., Mulvey and Sheppard, Academic Press, pp. 93-137 (1991).

*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.





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OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)

*Examiner Initial	Cite No.	
Pb	L	POSTEK, MICHAEL T., "The Scanning Electron Microscope," <u>Handbook of Charged Particle Optics</u> , edited by Jon Orloff, CRC Press LLC, 1997; Ch. 9, pp.363-382.
Pb	M	PURCELL, E.M., "The Focusing of Charged Particles by a Spherical Condenser," <u>Phys. Rev.</u> , 54, pp. 818-826 (1938).
Pb	N	SAR-EL, H.Z., "Criterion for Comparing Analyzers," <u>The Review of Scientific Instruments</u> , Vol. 41, No. 4, 561-564 (1970).
EXAMINER	DATE CONSIDERED	
Paul Surgo	12/13/02	

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